Application/Control No.	Applicant(s)/Patent under Reexamination		
10/724,325	CRUZ ET AL.		
Examiner	Art Unit		
Paul D. Kim	3720		

SEARCHED					
Class	Subclass	Date	Examiner		
29	592.1 825 827 831 832 846	4/11/2006	PK		
174	52.4				
257	678 684				
438	118	₩			
-					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
-					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Consulted Sara Crane (257) No Search	4/11/2006	PK	
Scott Geyer (438)	4/11/2006	PK	
Carl Arbes (29)	4/12/2006	PK	
Text Search EAST/NPL (IEEE)	4/12/2006	PK	
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